

Newsletter 10

Hello everybody,

I have received information about two image processing and computer vision events; although they are not directly related to IAPR TC10's topics, I include them in this mailout for everybody's benefit, as you may be interested in participating in these events.

First, an IEEE workshop on computer vision applications, where document analysis is explicitly mentioned as one of the topics:

Second IEEE Workshop on Applications of Computer Vision
Sarasota, Florida
December 5 - 7, 1994

CALL FOR PAPERS

GENERAL CHAIR:

Allen Hanson, University of Massachusetts, Amherst

PROGRAM CO-CHAIRS:

Bruce Flinchbaugh, Texas Instruments
&
Yasuo Nakagawa, Hitachi

LOCAL ARRANGEMENTS CHAIR:

Kevin Bowyer, University of South Florida

PROGRAM COMMITTEE:

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Henry Baird, AT&T Bell Laboratories
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Keith Nishihara, Teleos Research
Shmuel Peleg, Hebrew University
Banavar Sridhar, NASA Ames Research Center
Sargur Srihari, SUNY Buffalo
Robin Strickland, University of Arizona
Mohan Trivedi, University of Tennessee
Larry Wolff, Johns Hopkins University

PROGRAM:

We invite computer vision researchers and practitioners to participate in the second IEEE Workshop on Applications of Computer Vision, to be held in Sarasota, Florida, December 5-7, 1994.

The goal of this workshop is to bring together an international forum of industrial, academic, and government researchers in order to present and discuss the application of computer vision techniques to various problem domains of practical significance. The intent is to foster a free exchange of ideas in order to promote the transfer of solutions from one application domain to another, and guide computer vision research in useful directions.

The program will consist of high quality contributed papers covering computer vision applications that include, but are not limited to, manufacturing, inspection, medical analysis, security monitoring, human-computer interaction, document analysis, environmental protection, photo interpretation, highway/vehicle systems, target recognition, cartography, and space operations. Emphasis should be on novel research aspects and/or performance benchmarking for a given application task.

SUBMISSIONS:

Six (6) copies of papers should be submitted in English to the address below by June 1, 1994:

Bruce Flinchbaugh, Texas Instruments MS 238, 13510 North Central Expressway, Dallas, TX 75243, U.S.A.

Papers should be limited to 30 double-spaced pages, including figures, using no smaller than a 12 point font. Papers should include a title page containing the names and addresses of the authors, and an abstract of up to 200 words. Please also include a second title page with the abstract but without the names and addresses of the authors.

Include a summary page -- no more than one page containing answers to the following questions (answer each question separately and in order; please number your answers):

- 1) What is the application area of the work reported in this paper?
- 2) How far has this work progressed to date? (Concept/theory only? Experimental implementation and evaluation? Performance benchmarked

against other works? Being used in practice? Available as product?)
3) What is the primary significance/advantage/originality of this work?
4) How does this paper relate to previously published work?

FURTHER INFORMATION:

For further information or a copy of the advance program and workshop registration information when available, write to either:

Allen Hanson, Computer Science Department, A213 Lederle Graduate Research Center, University of Massachusetts, Amherst, MA 01003, U.S.A.

or

Workshop on Applications of Computer Vision, IEEE Computer Society, 1730 Massachusetts Avenue NW, Washington, DC 20036, U.S.A.

IMPORTANT DATES:

June 1, 1994: Paper Submission Deadline

July 31, 1994: Notification of Acceptance

September 1, 1994: Final Paper Due

Second, some update information about the first IEEE conf. on image processing:

UPDATE UPDATE UPDATE UPDATE UPDATE UPDATE UPDATE

FIRST IEEE INTERNATIONAL CONFERENCE ON IMAGE PROCESSING
November 13-16, 1994
Austin Convention Center, Austin, Texas, USA

Dear Colleague:

Our records indicate that you are on the ICIP electronic mailing list. We are therefore happy to be able to inform you of current events involving ICIP-94.

First, we are developing an exciting program that will include:

4 Tutorials:

M. Vetterli & J. Kovacevic on Wavelets
B. Girod on Compression of Still and Moving Images
R. Haralick on Mathematical Morphology
R. Blahut on Imaging Systems

3 Plenary Talks:

Paul Lauterbur, Univ. of Illinois at Urbana-Champaign
Peter Burt, Sarnoff Labs
Gary Starkweather, Apple Computer

6 Special Sessions:

Image Processing Education (R. Bamberg & J. Cozzens)
Signal Processing in Magnetic Resonance Imaging (Z. Liang)
Mathematical Morphology (D. Schonfeld & I. Pitas)
Nonlinear Dynamics in Image Processing (G. Sapiro & A. Tannenbaum)
Imaging Modalities (J. Quistgaard)
Electronic Imaging (C. Bouman and J. Allebach)

In addition there will be an exciting Product Exhibition featuring over 25 booths displaying today's state-of-the-art commercial image processing hardware, software, and accessories. This will be held in the Exhibit Hall at the Austin Convention Center.

As of February 23, 1994 (today) we have received over 700 paper submissions to ICIP-94 - attesting to the excitement that the conference has engendered in the image processing community. And certainly, presenting a challenge to the ICIP-94 Technical Program Committee to conduct a timely review process!

Nevertheless, it is necessary to announce an EXTENDED DUE DATE for further submissions to ICIP-94. This is made necessary because of an error by IEEE Publishing - the ICIP Call for Papers was inadvertently omitted from the recent issues of the IEEE Transactions on Image Processing and the IEEE Transactions on Signal Processing. Since these are our primary means of communicating with the members of the IEEE Signal Processing Society, we felt it necessary to give all SP Society members a chance to participate by advertising in the next available issue - with an extended due date:

EXTENDED ICIP-94 SUBMISSION DEADLINE: MARCH 15, 1994.

Naturally, this applies to everyone. If you would like another copy of the electronic version of the ICIP-94 Call for Papers, please let us know at icip@pine.ece.utexas.edu with the message "CFP Please."

Please note that the above extended deadline is STRICT. Submissions that are postmarked later than March 15, 1994 will not be accepted. This is necessary to ensure a fluid review process.

We look forward to seeing you in Austin!

THE ORGANIZING COMMITTEE
OF THE
FIRST IEEE INTERNATIONAL CONFERENCE ON IMAGE PROCESSING
November 13-16, 1994
Austin Convention Center, Austin, Texas, USA

Last, but not least, the IAPR SSPR'94 has also extended its submission
deadline to March 15th. Here is the message I was asked to forward.

Dear Machine Vision/Pattern Recognition community member:

Following the extension of deadline for submitting papers to
ICPR, the deadline for SSPR'94 has also been extended and is
March 15, 1994. The location of the Workshop was set to be
Nahariya, a nice Mediteranean resort town in the north of Israel.

Enclosed please find an updated Call for Papers.

Hope you will consider submission to SSPR'94.

Sincerely,

Dov Dori.

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Call for Papers

SSPR'94
International Workshop on
Syntactic and Structural Pattern Recognition

October 4-6 1994
NAHARIYA, ISRAEL

General Information:

Syntactic and structural pattern recognition encompasses all aspects
of pattern recognition that are related to the structure and/or syntax
of the patterns under consideration as a basis for their recognition.

SSPR'94 is the fifth workshop in a series of workshops organized by
the Technical Committee on SSPR of the International Association for
Pattern Recognition (IAPR), and held traditionally in conjunction with
the large IAPR International Conference on Pattern Recognition (ICPR),
held in October 1994 in Jerusalem.

The goal of this workshop is to provide a forum for discussing
issues related to syntactic and structural pattern recognition.
These issues include, but are not limited to, the following issues:

- General methodology.
- Machine learning and grammatical inference.
- Structured document image analysis: handwriting, maps, technical drawings.
- Speech and one-dimensional signal analysis.
- Structural methods in image processing.
- Shape analysis.
- Structural methods in computer vision.

We solicit contributions of two types:

- Research papers (extended abstracts limited to 10 double-spaced pages)
- Position papers (about any of the relevant issues).

The workshop will feature paper presentations, discussions and
panels based on position papers submitted, and invited speakers.

The abstracts of the papers will appear in a conference proceedings.
The papers presented at the Workshop will be published in a book format.

Location

The venue of the Workshop will be in Karlton Hotel, Nahariya.
Nahariya is a Mediteranean resort town, 40 minutes drive north of Haifa.
The weather in October is very nice and a tour to high-tech industry and
a number of touristic attractions in the Galilee is planned.

Important Dates in 1994:

March 15: Paper Submission.
June 1: Notification of Acceptance.
July 1: Final Abstract Submission.
Camera Ready Paper at the Workshop.

Program Committee

Co-Chairmen: Dov Dori and Alfred Bruckstein
H. Baird - AT&T Bell Labs, Murray Hill, NJ, USA
R. Basri - Weizmann Inst., Rehovot, Israel
H. Bunke - University of Bern, Switzerland
D. Doermann - University of Maryland, College Park, USA
R.M. Haralick - University of Washington, Seattle, USA

H. Freeman - Rutgers University, NJ, USA
R. Kasturi - Penn. State, University Park, PA, USA
N. Kiryati - Technion, Haifa, Israel
M. Lindenbaum - Technion, Haifa, Israel
R. Mohr - Institut Polytechnique, Grenoble, France
H. Noltemeier, University of Wuerzburg, Germany
T. Pavlidis, SUNY at Stony Brook, NY, USA
A. Rosenfeld - U. of Maryland, College Park, USA
A. Sanfeliu - Polytechnic of Catalonia, Barcelona, Spain
G. Sanniti di Baja - NRC, Napoli, Italy
C.Y. Suen - Concordia University, Montreal, Canada
K. Tombre, INRIA & CRIN/CNRS, Nancy, France
K. Yamamoto - Electroterchnical Laboratory, Japan
P.S.P. Wang - Northeastern, Boston, MA, USA
H. Wolfson - TAU, Tel Aviv, Israel

Workshop Secretariat and paper submission (three copies):
Ms. Nilly Schnap
Faculty of Industrial Engineering and Management
Technion, Israel Institute of Technology
Technion City, Haifa 32000, ISRAEL

Registration email ierns01@technion.technion.ac.il

Correspondence e-mail: SSPR94@ie.technion.ac.il

I hope this information can be useful to at least some of you. And for those who had already received all this info via other channels, please excuse me.

Sincerely,

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